Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/734,905	HWANG ET AL.	
Examiner	Art Unit	
Sun J Lin	2825	

	SEAR	CHED	
Class	Subclass	Date	Examiner
716	2	3/5/2005	JSL
716	16	3/5/2005	JSL
716	17	3/5/2005·	JSL
716	18	3/5/2005	JSL
		ī	

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
·			
İ			
	T		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
IEEE .	3/3/2005	JSL	
EAST [USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB]	3/5/2005	JSL	
GOOGLE	3/5/2005	JSL	
IEEE	3/5/2005	JSL	